

TOSHIBA MOS DIGITAL INTEGRATED CIRCUIT SILICON GATE CMOS

524,288 WORDS × 8 BIT STATIC RAM

DESCRIPTION

The TC554001FI/FTI is a 4,194,304-bit static random access memory (SRAM) organized as 524,288 words by 8 bits. Fabricated using Toshiba's CMOS Silicon gate process technology, this device operates from a single $5V \pm 10\%$ power supply. Advanced circuit technology provides both high speed and low power at an operating current of 10mA/MHz(typ) and minimum cycle time of 85 ns. It is automatically placed in low-power mode at $140 \mu A$ standby current (max) when chip enable (CE) is asserted high. There are two control inputs. CE is used to select the device and for data retention control, and output enable (OE) provides fast memory access. This device is well suited to various microprocessor system applications where high speed, low power and battery backup are required. And, with a guaranteed operating range of -40 to $85^\circ C$, the TC554001FI/FTI can be used in environments exhibiting extreme temperature conditions. The TC554001FI/FTI is available in a standard plastic 32-pin small-outline package(SOP) and 32-pin thin-small-outline package(TSOP).

FEATURES

- Low-power dissipation
Operating: 55 mW/MHz (typical)
- Standby current of $8 \mu A$ (maximum) at $T_a = 25^\circ C$
- Single power supply voltage of $5V \pm 10\%$
- Power down features using CE
- Data retention supply voltage of 2.0 to 5.5 V
- Directly TTL compatibility for all inputs and outputs
- Wide operating temperature range of -40° to $85^\circ C$

- Access Time (maximum)

	TC551001FI/FTI	
	-85L	-10L
Access Time	85 ns	100 ns
CE Access Time	85 ns	100 ns
OE Access Time	45 ns	50 ns

- Package:

SOP32-P-525-1.27 (FI) (Weight: 1.14 g typ)
TSOP II 32-P-400-1.27 (FTI) (Weight: 0.51 g typ)

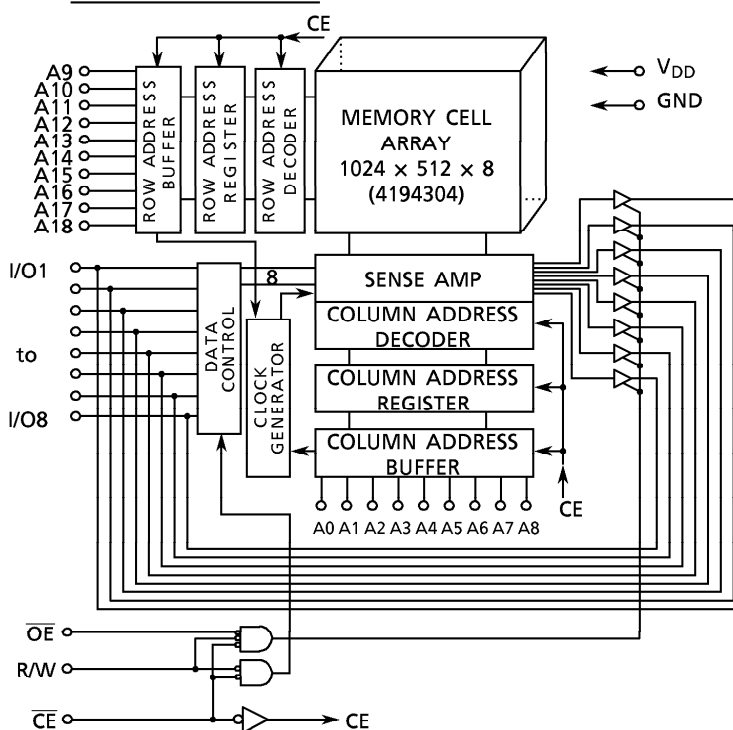
PIN ASSIGNMENT (TOP VIEW)

32 PIN FI/FTI			
A18	1	32	V _{DD}
A16	2	31	A15
A14	3	30	A17
A12	4	29	R/W
A7	5	28	A13
A6	6	27	A8
A5	7	26	A9
A4	8	25	A11
A3	9	24	OE
A2	10	23	A10
A1	11	22	CE
A0	12	21	I/O8
I/O1	13	20	I/O7
I/O2	14	19	I/O6
I/O3	15	18	I/O5
GND	16	17	I/O4

PIN NAMES

A0 to A18	Address Inputs
R/W	Read/Write Control
OE	Output Enable
CE	Chip Enable
I/O1 to I/O8	Data Input/Output
V _{DD}	Power (+ 5 V)
GND	Ground

BLOCK DIAGRAM



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OPERATION MODE

OPERATION MODE	\overline{CE}	\overline{OE}	R/W	I/O1 to I/O8	POWER
Read	L	L	H	D _{OUT}	I _{DDO}
Write	L	x	L	D _{IN}	I _{DDO}
Output Disabled	L	H	H	High-Z	I _{DDO}
Standby	H	x	x	High-Z	I _{DDS}

Note: x = don't care. H=logic high. L=logic low.

ABSOLUTE MAXIMUM RATINGS

SYMBOL	RATING	VALUE	UNIT
V _{DD}	Power Supply Voltage	- 0.3 to 7.0	V
V _{IN}	Input Voltage	- 0.3* to 7.0	V
V _{I/O}	Input and Output Voltage	- 0.5 to V _{DD} + 0.5	V
P _D	Power Dissipation	0.6	W
T _{solder}	Soldering Temperature (10 s)	260	°C
T _{strg.}	Storage Temperature	- 55 to 150	°C
T _{opr.}	Operating Temperature	- 40 to 85	°C

* - 3.0 V when measured at a pulse width of 50 ns

DC RECOMMENDED OPERATING CONDITIONS ($T_a = -40^\circ$ to 85°C)

SYMBOL	PARAMETER	MIN	TYP	MAX	UNIT
V_{DD}	Power Supply Voltage	4.5	5.0	5.5	V
V_{IH}	Input High Voltage	2.4	–	$V_{DD} + 0.3$	V
V_{IL}	Input Low Voltage	-0.3^*	–	0.6	V
V_{DH}	Data Retention Supply Voltage	2.0	–	5.5	V

* -3.0 V when measured at a pulse width of 50 ns**DC CHARACTERISTICS** ($T_a = -40^\circ$ to 85°C , $V_{DD} = 5\text{ V} \pm 10\%$)

SYMBOL	PARAMETER	TEST CONDITION			MIN	TYP	MAX	UNIT
I _{IL}	Input Leakage Current	V _{IN} = 0 V to V _{DD}			–	–	± 1.0	μA
I _{OH}	Output High Current	V _{OH} = 2.4 V			– 1.0	–	–	mA
I _{OL}	Output Low Current	V _{OL} = 0.4 V			2.1	–	–	mA
I _{LO}	Output Leakage Current	CE = V _{IH} or R/W = V _{IL} or OE = V _{IH} V _{OUT} = 0 V to V _{DD}			–	–	± 1.0	μA
I _{DDO1}	Operating Current	CE = V _{IL} and R/W = V _{IH} I _{OUT} = 0 mA Other Inputs = V _{IH} /V _{IL}	Tcycle	min	–	–	80	mA
				1 μs	–	15	–	
I _{DDO2}		CE = 0.2 V and R/W = V _{DD} –0.2 V I _{OUT} = 0 mA Other Inputs = V _{DD} –0.2 V/0.2 V	Tcycle	min	–	–	70	mA
				1 μs	–	10	–	
I _{DDS1}	Standby Current	CE = V _{IH}			–	–	3	mA
I _{DDS2}		CE = V _{DD} –0.2 V V _{DD} = 2.0 to 5.5 V	Ta = 25°C		–	4	8	μA
			Ta = –40° to 85°C		–	–	140	

CAPACITANCE ($T_a = 25^\circ\text{C}$, $f = 1\text{ MHz}$)

SYMBOL	PARAMETER	TEST CONDITION	MAX	UNIT
C_{IN}	Input Capacitance	$V_{IN} = \text{GND}$	10	pF
C_{OUT}	Output Capacitance	$V_{OUT} = \text{GND}$	10	pF

Note: This parameter is periodically sampled and is not 100% tested.

AC CHARACTERISTICS AND OPERATING CONDITIONS(Ta = - 40° to 85°C, V_{DD} = 5 V ± 10%)READ CYCLE

SYMBOL	PARAMETER	TC554001FI/FTI				UNIT
		-85L		-10L		
		MIN	MAX	MIN	MAX	
t _{RC}	Read Cycle Time	85	–	100	–	ns
t _{ACC}	Address Access Time	–	85	–	100	
t _{CO}	Chip Enable Access Time	–	85	–	100	
t _{OE}	Output Enable Access Time	–	45	–	50	
t _{COE}	Chip Enable Low to Output in Active	5	–	5	–	
t _{OEE}	Output Enable Low to Output Active	0	–	0	–	
t _{OD}	Chip Enable Hige to Output High-Z	–	35	–	40	
t _{ODO}	Output Enable Hige to Output High-Z	–	35	–	40	
t _{OH}	Output Data Hold Time	10	–	10	–	

WRITE CYCLE

SYMBOL	PARAMETER	TC554001FI/FTI				UNIT
		-85L		-10L		
		MIN	MAX	MIN	MAX	
t _{WC}	Write Cycle Time	85	–	100	–	ns
t _{WP}	Write Pulse Width	55	–	60	–	
t _{CW}	Chip Enable to End of Write	70	–	80	–	
t _{AS}	Address Setup Time	0	–	0	–	
t _{WR}	Write Recovery Time	0	–	0	–	
t _{ODW}	R/W Low to Output High-Z	–	35	–	40	
t _{OEW}	R/W High to Output Active	0	–	0	–	
t _{DS}	Data Setup Time	35	–	40	–	
t _{DH}	Data Hold Time	0	–	0	–	

AC TEST CONDITIONS

Output Load: 100 pF + one TTL gate

Input Pulse Level: 0.4 V, 2.6 V

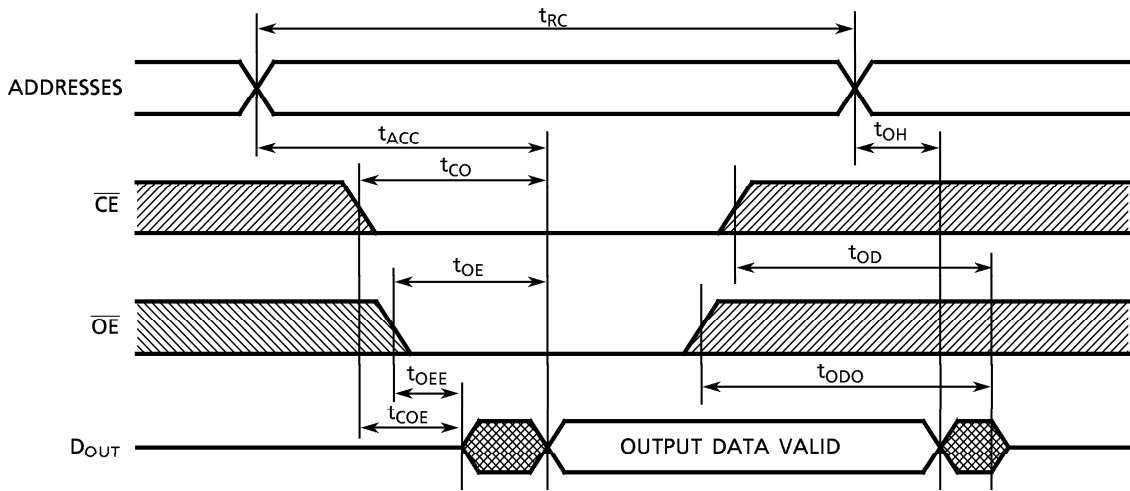
Timing Measurements: 1.5 V

Reference Level: 1.5 V

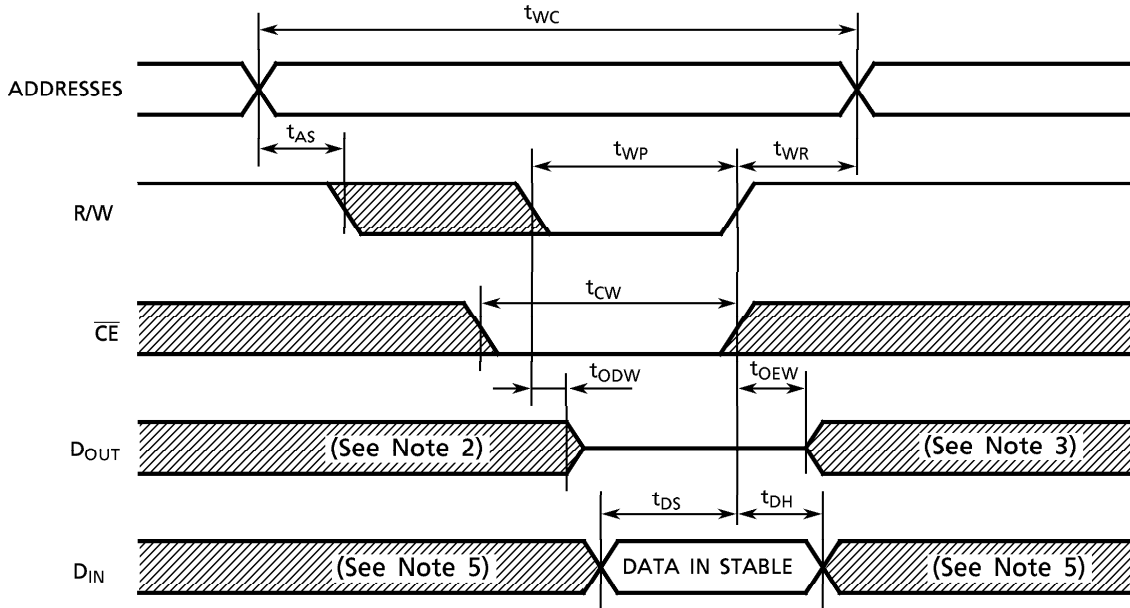
t_r, t_f: 5 ns

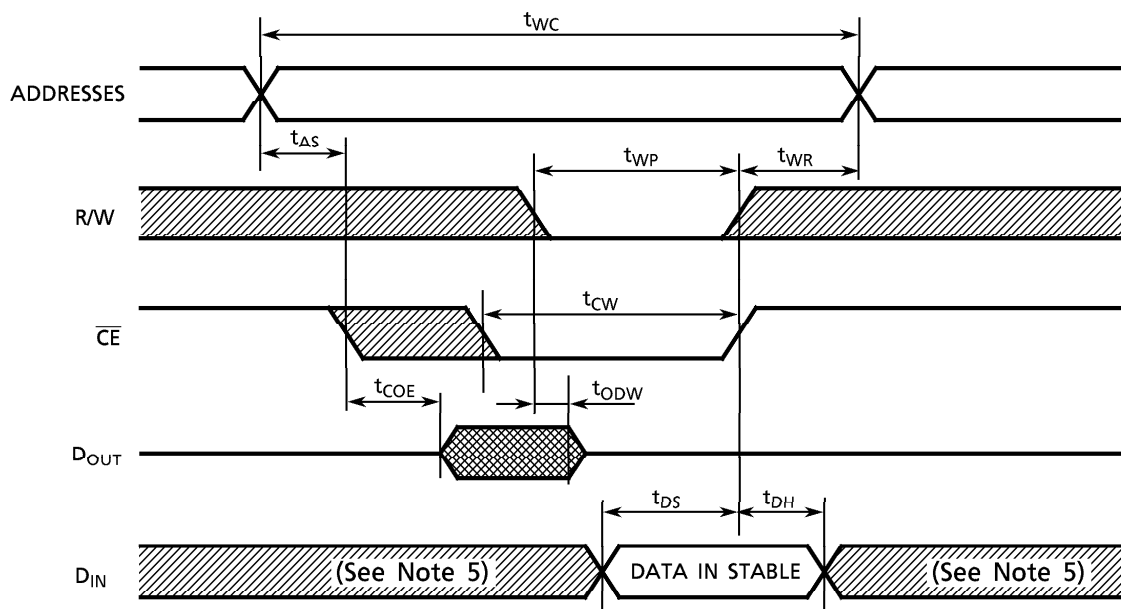
TIMING WAVEFORMS

READ CYCLE (See Note 1)



WRITE CYCLE 1 (R/W CONTROLLED) (See Note 4)

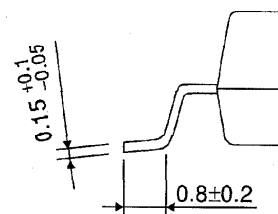
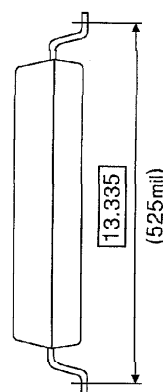
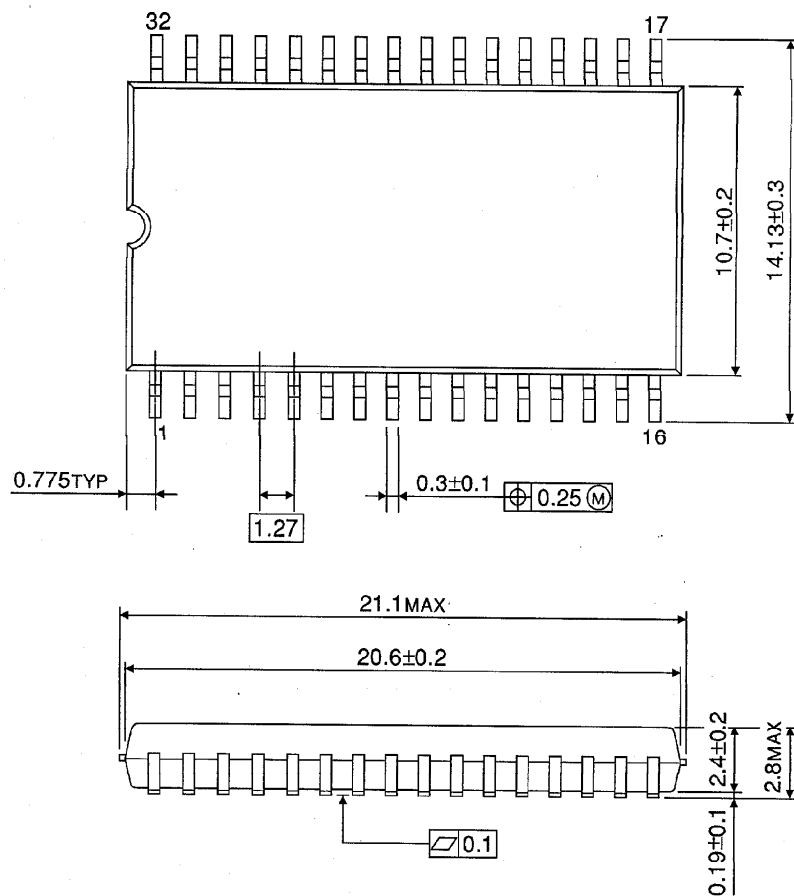


WRITE CYCLE 2 (\overline{CE} CONTROLLED) (See Note 4)

- (1) R/W remains High for Read Cycle.
- (2) If \overline{CE} goes coincident with or after R/W goes LOW, the output will remain at high impedance.
- (3) If \overline{CE} goes HIGH coincident with or before R/W goes HIGH, the output will remain at high impedance.
- (4) IF \overline{CE} is HIGH during the write cycle, the outputs will remain at high impedance.
- (5) Because I/O signals may be in the output state at this time, input signals of reverse polarity must not be applied.

PACKAGE DIMENSIONS (SOP32-P-525-1.27)

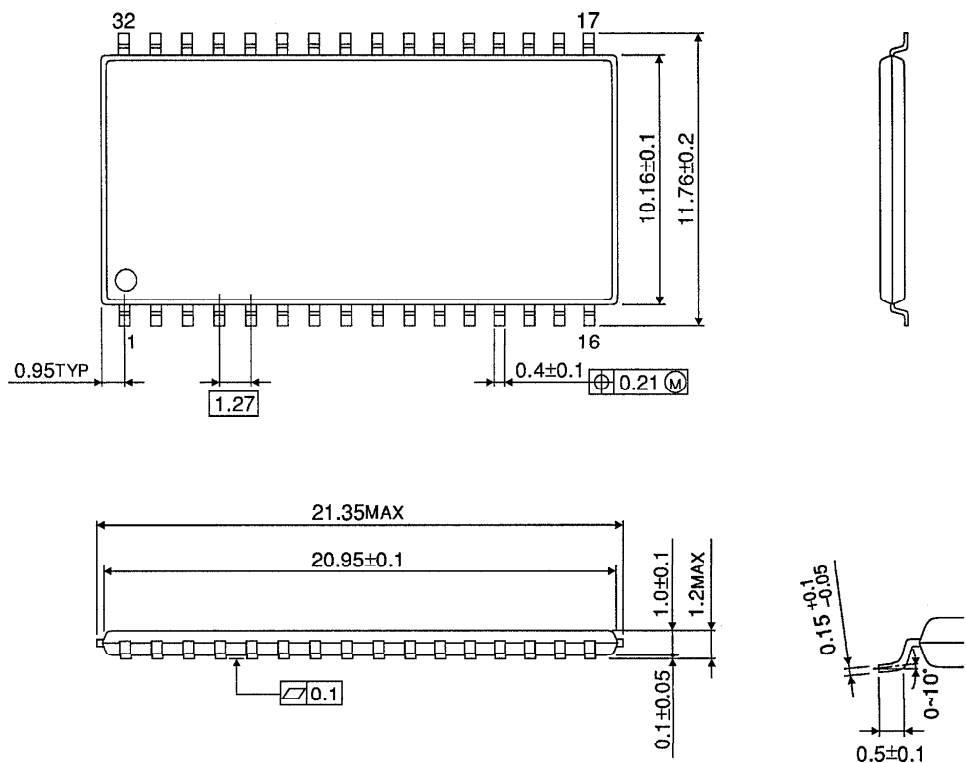
Unit in mm



Weight: 1.14 g (typ)

PACKAGE DIMENSIONS (TSOPII 32-P-400-1.27)

Unit in mm



Weight: 0.51 g (typ)